

# 74ALVT16823

18-bit bus-interface D-type flip-flop with reset and enable;  
3-state

Rev. 6 — 20 October 2020

Product data sheet

## 1. General description

The 74ALVT16823 is an 18-bit positive-edge triggered D-type flip-flop with 3-state outputs, reset and enable.

The device can be used as two 9-bit flip-flops or one 18-bit flip-flop. The device features clock (nCP), clock enable (nCE), master reset (nMR) and output enable (nOE), inputs each controlling 9-bits. When nCE is LOW, the flip-flops will store the state of their individual D-inputs that meet the set-up and hold time requirements on the LOW-to-HIGH clock (nCP) transition. A HIGH on nOE causes the outputs to assume a high-impedance OFF-state. Operation of the nOE input does not affect the state of the flip-flops. A LOW on nMR will reset the flip-flops LOW. Bus hold data inputs eliminate the need for external pull-up resistors to define unused inputs

## 2. Features and benefits

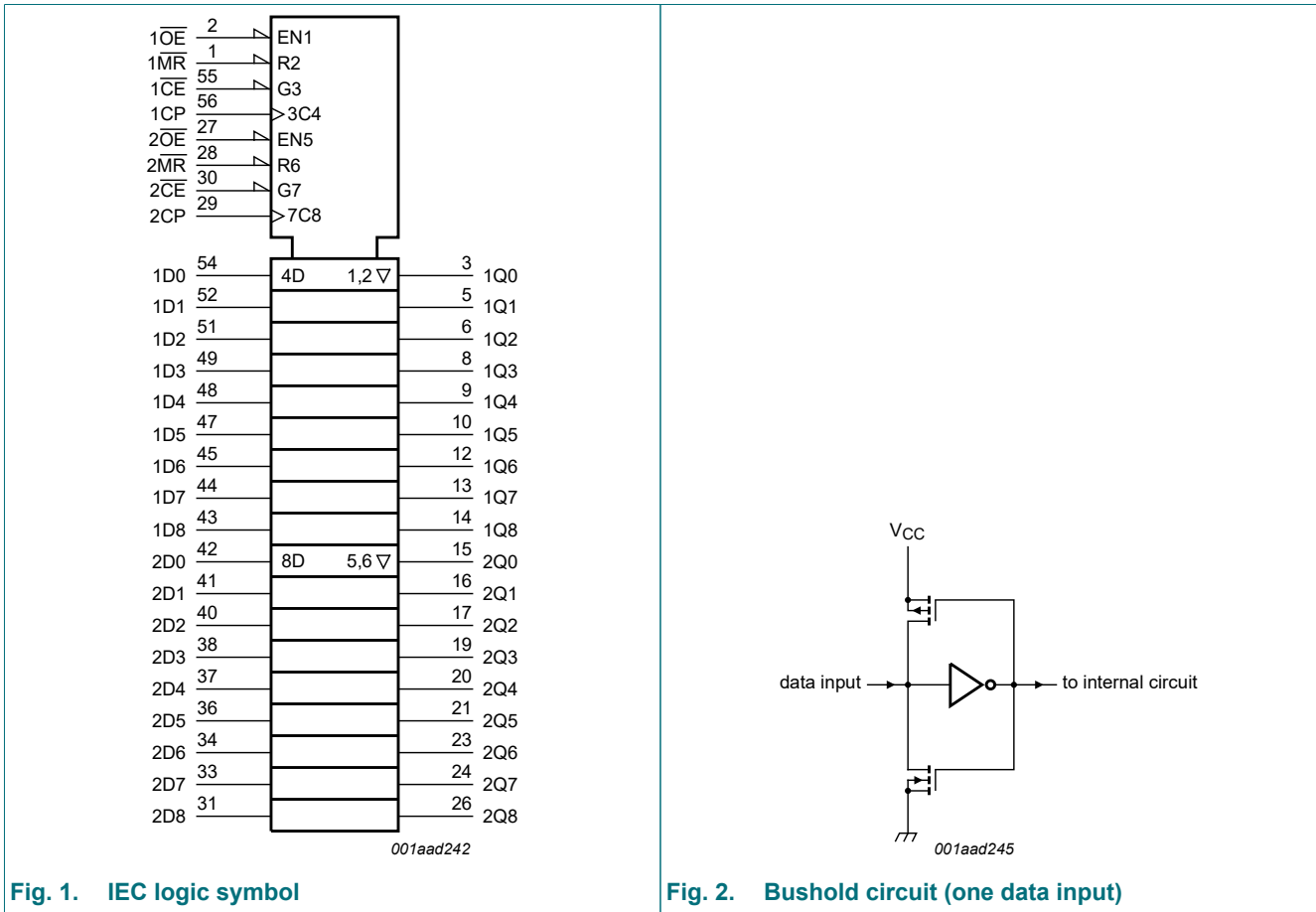
- Wide supply voltage range from 2.3 V to 3.6 V
- Overvoltage tolerant inputs to 5.5 V
- BiCMOS high speed and output drive
- Direct interface with TTL levels
- Bus hold on data inputs
- Power-up 3-state
- I<sub>OFF</sub> circuitry provides partial Power-down mode operation
- Two sets of high speed parallel registers with positive edge-triggered D-type flip-flops
- Ideal where high speed, light loading, or increased fan-in are required with MOS microprocessors
- Live insertion and extraction permitted
- Power-up reset
- No bus current loading when output is tied to 5 V bus
- Output capability: +64 mA to -32 mA
- Latch-up performance exceeds 500 mA per JESD 78 Class II Level B
- ESD protection:
  - MIL STD 883, method 3015: exceeds 2000 V
  - MM: exceeds 200 V
- Specified from -40 °C to 85 °C

## 3. Ordering information

Table 1. Ordering information

Type number	Package			Version
	Temperature range	Name	Description	
74ALVT16823DGG	-40 °C to +85 °C	TSSOP56	plastic thin shrink small outline package; 56 leads; body width 6.1 mm	SOT364-1

### 4. Functional diagram



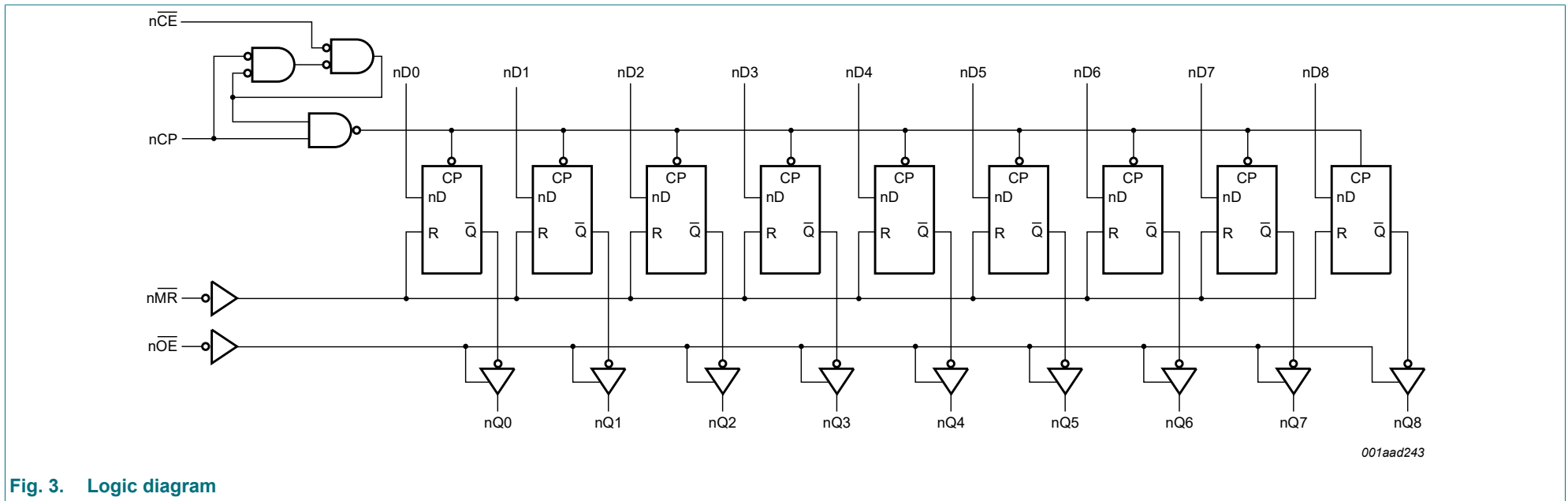


Fig. 3. Logic diagram

## 5. Pinning information

### 5.1. Pinning

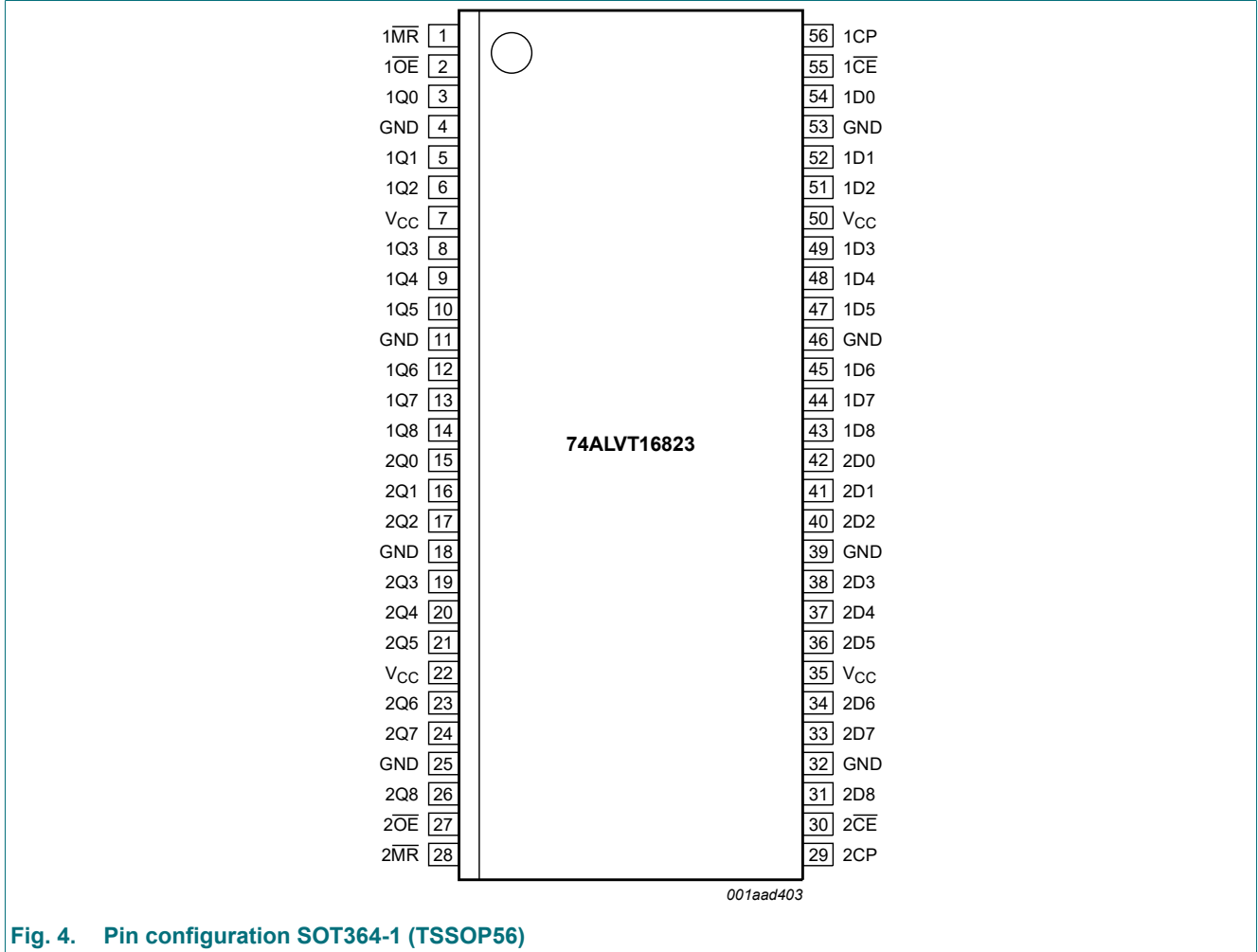


Fig. 4. Pin configuration SOT364-1 (TSSOP56)

### 5.2. Pin description

Table 2. Pin description

Symbol	Pin	Description
1D0, 1D1, 1D2, 1D3, 1D4, 1D5, 1D6, 1D7, 1D8	54, 52, 51, 49, 48, 47, 45, 44, 43	data inputs
1Q0, 1Q1, 1Q2, 1Q3, 1Q4, 1Q5, 1Q6, 1Q7, 1Q8	3, 5, 6, 8, 9, 10, 12, 13, 14	data outputs
2D0, 2D1, 2D2, 2D3, 2D4, 2D5, 2D6, 2D7, 2D8	42, 41, 40, 38, 37, 36, 34, 33, 31	data inputs
2Q0, 2Q1, 2Q2, 2Q3, 2Q4, 2Q5, 2Q6, 2Q7, 2Q8	15, 16, 17, 19, 20, 21, 23, 24, 26	data outputs
1MR, 2MR	1, 28	master reset input (active-LOW)
1OE, 2OE	2, 27	output enable inputs (active LOW)
1CP, 2CP	56, 29	clock pulse inputs (active rising edge)
1CE, 2CE	55, 30	clock enable input (active-LOW)
GND	4, 11, 18, 25, 32, 39, 46, 53	ground (0 V)
V <sub>CC</sub>	7, 22, 35, 50	supply voltage

## 6. Functional description

**Table 3. Function table**

*H = HIGH voltage level; h = HIGH voltage level one set-up time prior to the LOW-to-HIGH clock transition;*

*L = LOW voltage level; l = LOW voltage level one set-up time prior to the LOW-to-HIGH clock transition;*

*NC = no change; X = don't care; Z = high-impedance OFF-state;*

*↑ = LOW-to-HIGH clock transition;  $\bar{\uparrow}$  = not a LOW-to-HIGH clock transition.*

Operating mode	Input					Output
	nOE	nMR	nCE	nCP	nDn	nQn
clear	L	L	X	X	X	L
load and read data	L	H	L	↑	h	H
					l	L
hold	L	H	H	$\bar{\uparrow}$	X	NC
high-impedance	H	X	X	X	X	Z

## 7. Limiting values

**Table 4. Limiting values**

*In accordance with the Absolute Maximum Rating System (IEC 60134); voltages are referenced to GND (ground = 0 V).*

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	supply voltage		-0.5	+4.6	V
V <sub>I</sub>	input voltage		[1] -0.5	+7.0	V
V <sub>O</sub>	output voltage	output in OFF-state or HIGH-state	[1] -0.5	+7.0	V
I <sub>IK</sub>	input clamping current	V <sub>I</sub> < 0 V	-	-50	mA
I <sub>OK</sub>	output clamping current	V <sub>O</sub> < 0 V	-	-50	mA
I <sub>O</sub>	output current	output in LOW-state	-	128	mA
		output in HIGH-state	-64	-	mA
T <sub>stg</sub>	storage temperature		-65	+150	°C
T <sub>j</sub>	junction temperature		[2] -	150	°C

[1] The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability.

## 8. Recommended operating conditions

**Table 5. Recommended operating conditions**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>V<sub>CC</sub> = 2.5 V</b>						
V <sub>CC</sub>	supply voltage		2.3	-	2.7	V
V <sub>I</sub>	input voltage		0	-	5.5	V
I <sub>OH</sub>	HIGH-level output current		-	-	-8	mA
I <sub>OL</sub>	LOW-level output current	none	-	-	8	mA
		current duty cycle ≤ 50 %; f ≥ 1 kHz	-	-	24	mA
Δt/Δv	input transition rise or fall rate	outputs enabled	-	-	10	ns/V
T <sub>amb</sub>	ambient temperature	in free air	-40	-	+85	°C

## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>V<sub>CC</sub> = 3.3 V</b>						
V <sub>CC</sub>	supply voltage		3.0	-	3.6	V
V <sub>I</sub>	input voltage		0	-	5.5	V
I <sub>OH</sub>	HIGH-level output current		-	-	-32	mA
I <sub>OL</sub>	LOW-level output current	none	-	-	32	mA
		current duty cycle ≤ 50 %; f ≥ 1 kHz	-	-	64	mA
Δt/Δv	input transition rise or fall rate	outputs enabled	-	-	10	ns/V
T <sub>amb</sub>	ambient temperature	in free air	-40	-	+85	°C

## 9. Static characteristics

**Table 6. Static characteristics**

At recommended operating conditions; Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
<b>V<sub>CC</sub> = 2.5 V ± 0.2 V</b>						
V <sub>IK</sub>	input clamping voltage	V <sub>CC</sub> = 2.3 V; I <sub>IK</sub> = -18 mA	-	-0.85	-1.2	V
V <sub>IH</sub>	HIGH-level input voltage		1.7	-	-	V
V <sub>IL</sub>	LOW-level input voltage		-	-	0.7	V
V <sub>OH</sub>	HIGH-level output voltage	V <sub>CC</sub> = 2.3 V to 2.7 V; I <sub>O</sub> = -100 μA	V <sub>CC</sub> - 0.2	V <sub>CC</sub>	-	V
		V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = -8 mA	1.8	2.5	-	V
V <sub>OL</sub>	LOW-level output voltage	V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = 100 μA	-	0.07	0.2	V
		V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = 24 mA	-	0.3	0.5	V
		V <sub>CC</sub> = 2.3 V; I <sub>O</sub> = 8 mA	-	-	0.4	V
V <sub>OL(pu)</sub>	power-up LOW-level output voltage	V <sub>CC</sub> = 2.7 V; I <sub>O</sub> = 1 mA; V <sub>I</sub> = V <sub>CC</sub> or GND [2]	-	-	0.55	V
I <sub>I</sub>	input leakage current	control pins				
		V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = V <sub>CC</sub> or GND	-	0.1	±1	μA
		V <sub>CC</sub> = 0 V to 2.7 V; V <sub>I</sub> = 5.5 V	-	0.1	10	μA
		I/O data pins [3]				
		V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = V <sub>CC</sub>	-	0.1	1	μA
	V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = 0 V	-	+0.1	-5	μA	
I <sub>OFF</sub>	power-off leakage current	V <sub>CC</sub> = 0 V; V <sub>I</sub> or V <sub>O</sub> = 0 V to 4.5 V	-	+0.1	±100	μA
I <sub>BHL</sub>	bus hold LOW current	data inputs; V <sub>CC</sub> = 2.3 V; V <sub>I</sub> = 0.7 V [4]	-	100	-	μA
I <sub>BHH</sub>	bus hold HIGH current	data inputs; V <sub>CC</sub> = 2.3 V; V <sub>I</sub> = 1.7 V [4]	-	-70	-	μA
I <sub>EX</sub>	external current	output HIGH-state when V <sub>O</sub> > V <sub>CC</sub> ; V <sub>O</sub> = 5.5 V; V <sub>CC</sub> = 2.3 V	-	10	125	μA
I <sub>O(pu pd)</sub>	power-up/power-down output current	V <sub>CC</sub> ≤ 1.2 V; V <sub>O</sub> = 0.5 V to V <sub>CC</sub> ; V <sub>I</sub> = GND or V <sub>CC</sub> [5]	-	1	±100	μA
I <sub>OZ</sub>	OFF-state output current	V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = V <sub>IL</sub> or V <sub>IH</sub>				
		output HIGH state; V <sub>O</sub> = 2.3 V	-	0.5	5	μA
		output LOW-state; V <sub>O</sub> = 0.5 V	-	+0.5	-5	μA

## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
I <sub>CC</sub>	supply current	V <sub>CC</sub> = 2.7 V; V <sub>I</sub> = GND or V <sub>CC</sub> ; I <sub>O</sub> = 0 A				
		outputs HIGH-state	-	0.04	0.1	mA
		outputs LOW-state	-	2.7	4.5	mA
		outputs disabled [6]	-	0.04	0.1	mA
ΔI <sub>CC</sub>	additional supply current	per input pin; V <sub>CC</sub> = 2.3 V to 2.7 V; one input at V <sub>CC</sub> - 0.6 V, other inputs at V <sub>CC</sub> or GND [7]	-	0.04	0.4	mA
C <sub>I</sub>	input capacitance	V <sub>I</sub> = 0 V or V <sub>CC</sub>	-	3	-	pF
C <sub>O</sub>	output capacitance	V <sub>IO</sub> = 0 V or 3.0 V	-	9	-	pF
<b>V<sub>CC</sub> = 3.3 V ± 0.3 V</b>						
V <sub>IK</sub>	input clamping voltage	V <sub>CC</sub> = 3.0 V; I <sub>IK</sub> = -18 mA	-	-0.85	-1.2	V
V <sub>IH</sub>	HIGH-level input voltage		2.0	-	-	V
V <sub>IL</sub>	LOW-level input voltage		-	-	0.8	V
V <sub>OH</sub>	HIGH-level output voltage	V <sub>CC</sub> = 3.0 V to 3.6 V; I <sub>O</sub> = -100 μA	V <sub>CC</sub> - 0.2	V <sub>CC</sub>	-	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = -32 mA	2.0	2.3	-	V
V <sub>OL</sub>	LOW-level output voltage	V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 100 μA	-	0.07	0.2	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 16 mA	-	0.25	0.4	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 32 mA	-	0.3	0.5	V
		V <sub>CC</sub> = 3.0 V; I <sub>O</sub> = 64 mA	-	0.4	0.55	V
V <sub>OL(pu)</sub>	power-up LOW-level output voltage	V <sub>CC</sub> = 3.6 V; I <sub>O</sub> = 1 mA; V <sub>I</sub> = V <sub>CC</sub> or GND [2]	-	-	0.55	V
I <sub>I</sub>	input leakage current	control pins				
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>CC</sub> or GND	-	0.1	±1	μA
		V <sub>CC</sub> = 0 V or 3.6 V; V <sub>I</sub> = 5.5 V	-	0.1	10	μA
		I/O data pins [3]				
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>CC</sub>	-	0.5	1	μA
		V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V	-	+0.1	-5	μA
I <sub>OFF</sub>	power-off leakage current	V <sub>CC</sub> = 0 V; V <sub>I</sub> or V <sub>O</sub> = 0 V to 4.5 V	-	0.1	±100	μA
I <sub>BHL</sub>	bus hold LOW current	data inputs; V <sub>CC</sub> = 3 V; V <sub>I</sub> = 0.8 V	75	130	-	μA
I <sub>BHH</sub>	bus hold HIGH current	data inputs; V <sub>CC</sub> = 3 V; V <sub>I</sub> = 2.0 V	-75	-140	-	μA
I <sub>BHLO</sub>	bus hold LOW overdrive current	data inputs; V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V to 3.6 V [8]	500	-	-	μA
I <sub>BHHO</sub>	bus hold HIGH overdrive current	data inputs; V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = 0 V to 3.6 V [8]	-500	-	-	μA
I <sub>EX</sub>	external current	output HIGH-state when V <sub>O</sub> > V <sub>CC</sub> ; V <sub>O</sub> = 5.5 V; V <sub>CC</sub> = 3.0 V	-	10	125	μA
I <sub>O(pu/pd)</sub>	power-up/power-down output current	V <sub>CC</sub> ≤ 1.2 V; V <sub>O</sub> = 0.5 V to V <sub>CC</sub> ; V <sub>I</sub> = GND or V <sub>CC</sub> [9]	-	1	±100	μA
I <sub>OZ</sub>	OFF-state output current	V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = V <sub>IL</sub> or V <sub>IH</sub>				
		output HIGH state; V <sub>O</sub> = 3.0 V	-	0.5	5	μA
		output LOW-state; V <sub>O</sub> = 0.5 V	-	+0.5	-5	μA

## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
I <sub>CC</sub>	supply current	V <sub>CC</sub> = 3.6 V; V <sub>I</sub> = GND or V <sub>CC</sub> ; I <sub>O</sub> = 0 A				
		outputs HIGH-state	-	0.06	0.1	mA
		outputs LOW-state	-	3.9	5.5	mA
		outputs disabled [6]	-	0.06	0.1	mA
ΔI <sub>CC</sub>	additional supply current	per input pin; V <sub>CC</sub> = 3 V to 3.6 V; one input at V <sub>CC</sub> - 0.6 V, other inputs at V <sub>CC</sub> or GND [7]	-	0.04	0.4	mA
C <sub>I</sub>	input capacitance	V <sub>I</sub> = 0 V or V <sub>CC</sub>	-	3	-	pF
C <sub>O</sub>	output capacitance	V <sub>I/O</sub> = 0 V or 3.0 V	-	9	-	pF

- [1] All typical values for V<sub>CC</sub> = 2.5 V ± 0.2 V are measured at V<sub>CC</sub> = 2.5 V and T<sub>amb</sub> = 25 °C.  
All typical values for V<sub>CC</sub> = 3.3 V ± 0.3 V are measured at V<sub>CC</sub> = 3.3 V and T<sub>amb</sub> = 25 °C.
- [2] For valid test results, data must not be loaded into the flip-flops after applying power.
- [3] Unused pins at V<sub>CC</sub> or GND.
- [4] Not guaranteed.
- [5] This parameter is valid for any V<sub>CC</sub> between 0 V and 1.2 V with a transition time of up to 10 ms.  
From V<sub>CC</sub> = 1.2 V to V<sub>CC</sub> = 2.5 V ± 0.2 V a transition time of 100 μs is permitted. This parameter is valid for T<sub>amb</sub> = 25 °C only.
- [6] I<sub>CC</sub> is measured with outputs pulled up to V<sub>CC</sub> or pulled down to ground.
- [7] This is the increase in supply current for each input at the specified voltage level other than V<sub>CC</sub> or GND.
- [8] This is the bus hold overdrive current required to force the input to the opposite logic state.
- [9] This parameter is valid for any V<sub>CC</sub> between 0 V and 1.2 V with a transition time of up to 10 ms.  
From V<sub>CC</sub> = 1.2 V to V<sub>CC</sub> = 3.3 V ± 0.3 V a transition time of 100 μs is permitted. This parameter is valid for T<sub>amb</sub> = 25 °C only.

## 10. Dynamic characteristics

**Table 7. Dynamic characteristics**

Voltages are referenced to GND (ground = 0 V); for test circuit see Fig. 9.

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
<b>V<sub>CC</sub> = 2.5 V ± 0.2 V</b>						
t <sub>PLH</sub>	LOW to HIGH propagation delay	nCP to nQn; see Fig. 5	1.5	2.9	4.5	ns
t <sub>PHL</sub>	HIGH-to-LOW propagation delay	nCP to nQn; see Fig. 5	1.4	2.7	4.2	ns
		nMR to nQn; see Fig. 7	1.5	2.7	4.2	ns
t <sub>PZH</sub>	OFF-state to HIGH propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	2.1	3.4	5.0	ns
t <sub>PZL</sub>	OFF-state to LOW propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	1.8	3.0	4.7	ns
t <sub>PHZ</sub>	HIGH to OFF-state propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	1.7	3.0	4.3	ns
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	n $\overline{OE}$ to nQn; see Fig. 8	1.4	2.3	3.3	ns
t <sub>su(H)</sub>	set-up time HIGH	nDn to nCP; see Fig. 6	1.0	0.5	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	1.0	0.2	-	ns
t <sub>su(L)</sub>	set-up time LOW	nDn to nCP; see Fig. 6	1.8	1.3	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	0.5	-0.1	-	ns
t <sub>h(H)</sub>	hold time HIGH	nDn to nCP; see Fig. 6	0.1	-1.4	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	1.0	0.2	-	ns
t <sub>h(L)</sub>	hold time LOW	nDn to nCP; see Fig. 6	0.1	-0.5	-	ns
		n $\overline{CE}$ to nCP; see Fig. 6	1.0	-0.1	-	ns

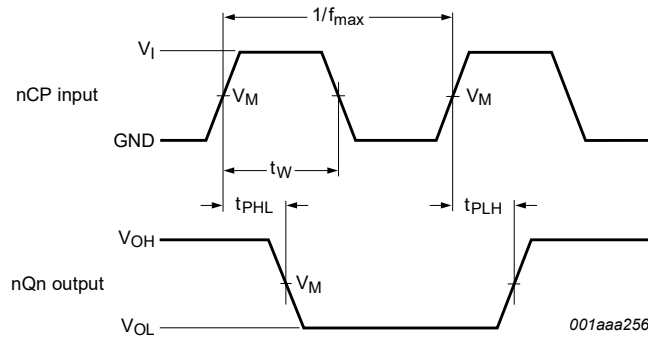


## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Symbol	Parameter	Conditions	T <sub>amb</sub> = -40 °C to +85 °C			Unit
			Min	Typ[1]	Max	
t <sub>WH</sub>	pulse width HIGH	nCP; see Fig. 5	2.0	0.8	-	ns
t <sub>WL</sub>	pulse width LOW	nCP	3.0	2.1	-	ns
		nMR; see Fig. 7	2.0	0.8	-	ns
t <sub>rec</sub>	recovery time	nMR to nCP; see Fig. 7	2.0	1.3	-	ns
f <sub>max</sub>	maximum frequency	CP; see Fig. 5	150	-	-	MHz
<b>V<sub>CC</sub> = 3.3 V ± 0.3 V</b>						
t <sub>PLH</sub>	LOW to HIGH propagation delay	nCP to nQn; see Fig. 5	1.0	2.3	3.1	ns
t <sub>PHL</sub>	HIGH-to-LOW propagation delay	nCP to nQn; see Fig. 5	1.0	2.1	2.9	ns
		nMR to nQn; see Fig. 7	1.0	2.3	2.9	ns
t <sub>PZH</sub>	OFF-state to HIGH propagation delay	nOE to nQn; see Fig. 8	1.7	2.7	4.0	ns
t <sub>PZL</sub>	OFF-state to LOW propagation delay	nOE to nQn; see Fig. 8	1.4	2.3	3.5	ns
t <sub>PHZ</sub>	HIGH to OFF-state propagation delay	nOE to nQn; see Fig. 8	2.2	3.1	4.0	ns
t <sub>PLZ</sub>	LOW to OFF-state propagation delay	nOE to nQn; see Fig. 8	1.8	2.6	3.5	ns
t <sub>su(H)</sub>	set-up time HIGH	nDn to nCP; see Fig. 6	1.0	0.5	-	ns
		nCE to nCP; see Fig. 6	1.0	0.1	-	ns
t <sub>su(L)</sub>	set-up time LOW	nDn to nCP; see Fig. 6	1.6	1.1	-	ns
		nCE to nCP; see Fig. 6	0.5	-0.5	-	ns
t <sub>h(H)</sub>	hold time HIGH	nDn to nCP; see Fig. 6	0.1	-0.7	-	ns
		nCE to nCP; see Fig. 6	1.0	0.5	-	ns
t <sub>h(L)</sub>	hold time LOW	nDn to nCP; see Fig. 6	0.1	-0.5	-	ns
		nCE to nCP; see Fig. 6	1.0	-0.1	-	ns
t <sub>WH</sub>	pulse width HIGH	nCP; see Fig. 5	1.5	0.7	-	ns
t <sub>WL</sub>	pulse width LOW	nCP	2.5	1.4	-	ns
		nMR; see Fig. 7	2.0	1.5	-	ns
t <sub>rec</sub>	recovery time	nMR to nCP; see Fig. 7	2.0	1.1	-	ns
f <sub>max</sub>	maximum frequency	CP; see Fig. 5	250	-	-	MHz

- [1] All typical values for V<sub>CC</sub> = 2.5 V ± 0.2 V are measured at V<sub>CC</sub> = 2.5 V and T<sub>amb</sub> = 25 °C.  
All typical values for V<sub>CC</sub> = 3.3 V ± 0.3 V are measured at V<sub>CC</sub> = 3.3 V and T<sub>amb</sub> = 25 °C.

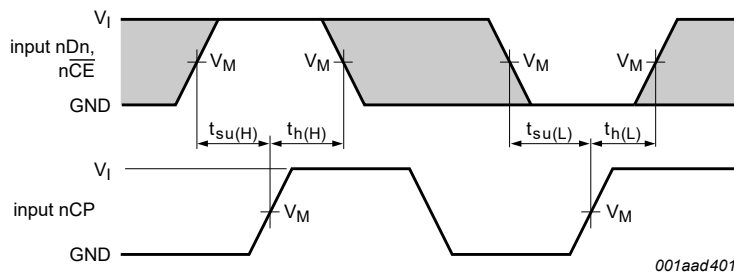
10.1. Waveforms and test circuit



Measurement points are given in [Table 8](#).

V<sub>OL</sub> and V<sub>OH</sub> are typical voltage output levels that occur with the output load.

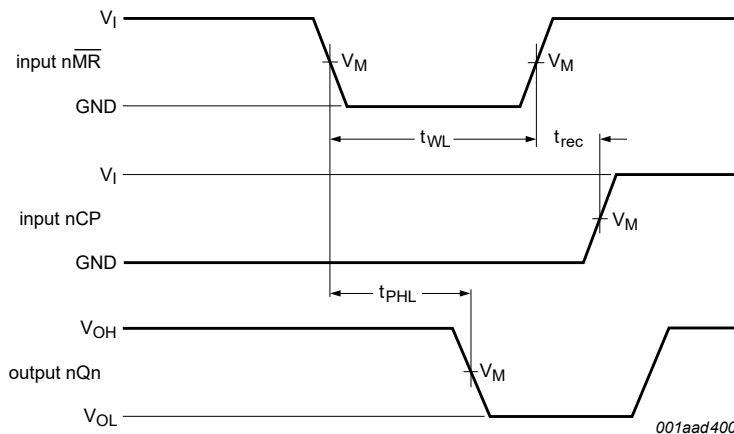
**Fig. 5. Propagation delay clock input (nCP) to output (nQn), clock pulse (nCP) width HIGH and maximum clock frequency**



Measurement points are given in [Table 8](#).

The shaded areas indicate when the input is permitted to change for predictable output performance.

**Fig. 6. Data set-up and hold times**

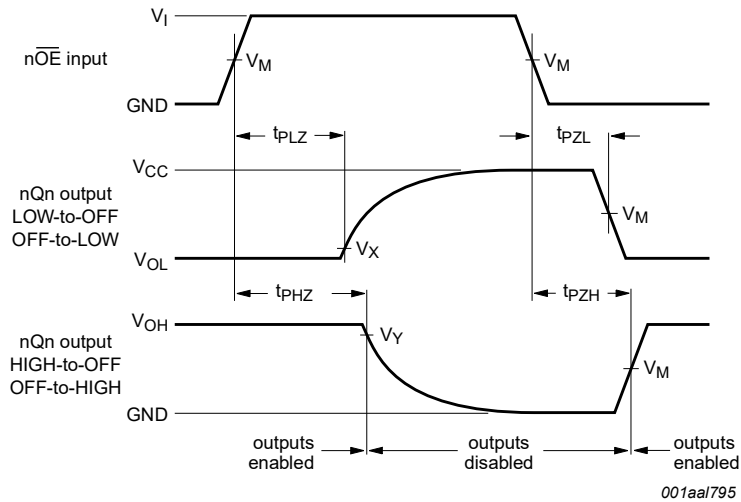


Measurement points are given in [Table 8](#).

V<sub>OL</sub> and V<sub>OH</sub> are typical voltage output levels that occur with the output load.

**Fig. 7. Master reset pulse width, master reset to output delay and master reset to clock recovery time**

18-bit bus-interface D-type flip-flop with reset and enable; 3-state



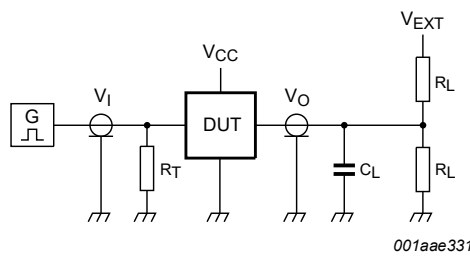
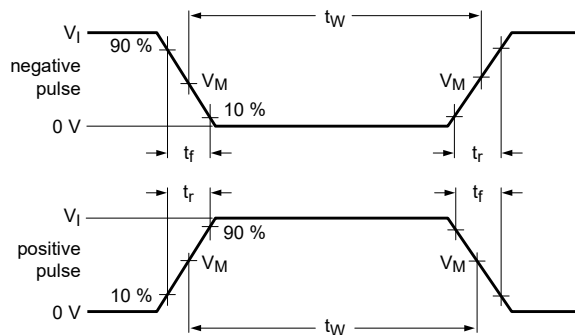
Measurement points are given in [Table 8](#).

$V_{OL}$  and  $V_{OH}$  are typical voltage output levels that occur with the output load.

**Fig. 8. OFF-state to HIGH and LOW propagation delays and LOW and HIGH to OFF-state propagation delays**

**Table 8. Measurement points**

$V_{CC}$	Input	Output		
	$V_M$	$V_M$	$V_X$	$V_Y$
$\leq 2.7\text{ V}$	$0.5 \times V_{CC}$	$0.5 \times V_{CC}$	$V_{OL} + 0.15\text{ V}$	$V_{OH} - 0.15\text{ V}$
$\geq 3.0\text{ V}$	$1.5\text{ V}$	$1.5\text{ V}$	$V_{OL} + 0.3\text{ V}$	$V_{OH} - 0.3\text{ V}$



Test data is given in [Table 9](#).

Definitions test circuit:

$R_L$  = Load resistance.

$C_L$  = Load capacitance including jig and probe capacitance.

$R_T$  = Termination resistance should be equal to output impedance  $Z_o$  of the pulse generator.

$V_{EXT}$  = Test voltage for switching times.

**Fig. 9. Test circuit for measuring switching times**

## 18-bit bus-interface D-type flip-flop with reset and enable; 3-state

Table 9. Test data

Input				Load		$V_{EXT}$		
$V_i$	$f_i$	$t_w$	$t_r, t_f$	$C_L$	$R_L$	$t_{PHZ}, t_{PZH}$	$t_{PLZ}, t_{PZL}$	$t_{PLH}, t_{PHL}$
3.0 V or $V_{CC}$ whichever is less	$\leq 10$ MHz	500 ns	$\leq 2.5$ ns	50 pF	500 $\Omega$	GND	6 V or $V_{CC} \times 2$	open

### 11. Package outline

TSSOP56: plastic thin shrink small outline package; 56 leads; body width 6.1 mm

SOT364-1

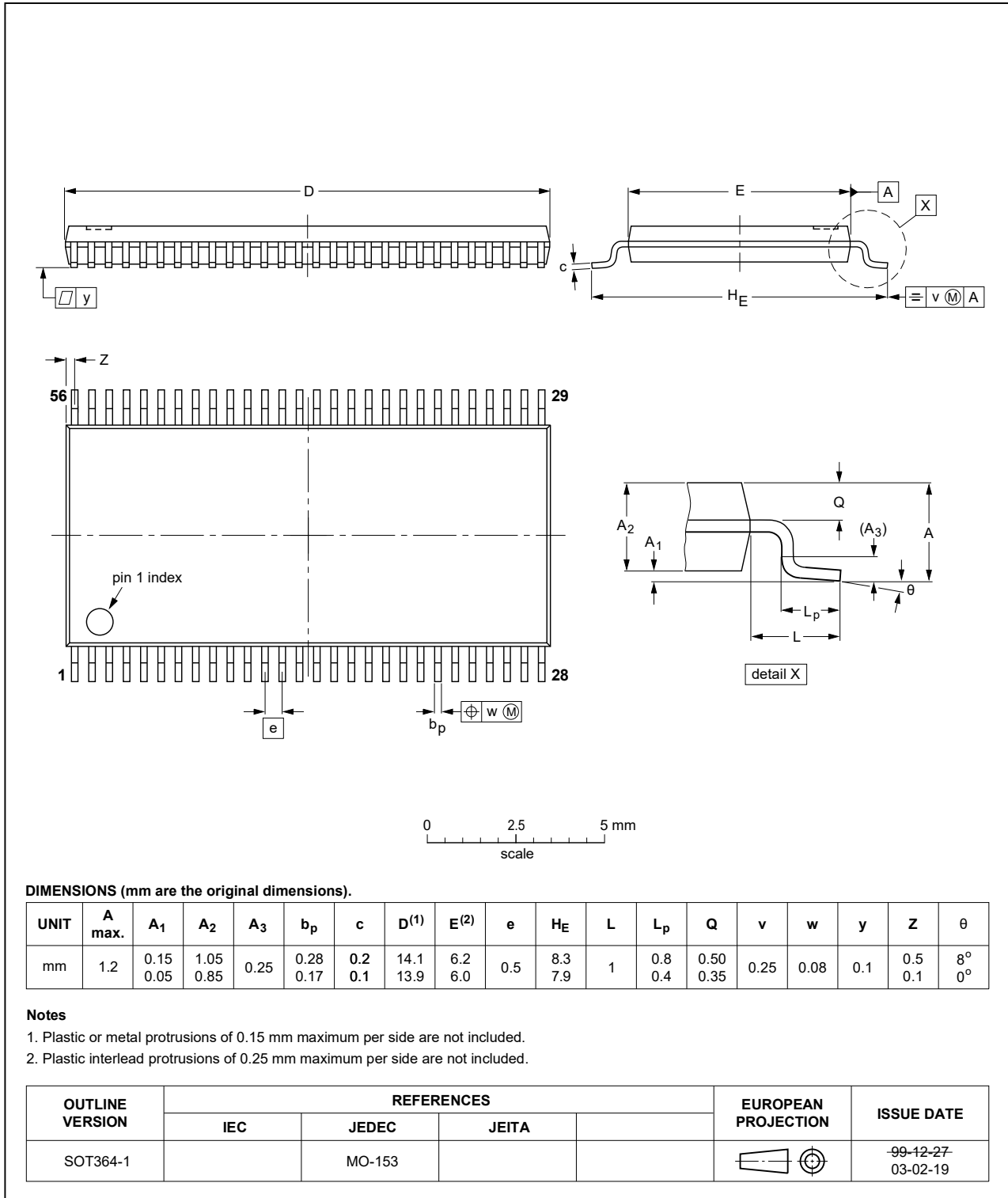


Fig. 10. Package outline SOT364-1 (TSSOP56)

## 12. Abbreviations

Table 10. Abbreviations

Acronym	Description
BiCMOS	Bipolar Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
MIL	Military
MM	Machine Model
MOS	Metal-Oxide Semiconductor
TTL	Transistor-Transistor Logic

## 13. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ALVT16823 v.6	20201020	Product data sheet	-	74ALVT16823 v.5
Modifications:	<ul style="list-style-type: none"> <li>Type number 74ALVT16823DL (SOT371-1 / SSOP56) removed.</li> <li><a href="#">Section 1</a> and <a href="#">Section 2</a> updated.</li> </ul>			
74ALVT16823 v.5	20180122	Product data sheet	-	74ALVT16823 v.4
Modifications:	<ul style="list-style-type: none"> <li>The format of this data sheet has been redesigned to comply with the identity guidelines of Nexperia.</li> <li>Legal texts have been adapted to the new company name where appropriate.</li> </ul>			
74ALVT16823 v.4	20050802	Product data sheet	-	74ALVT16823 v.3
Modifications:	<ul style="list-style-type: none"> <li>The format of this data sheet has been redesigned to comply with the new presentation and information standard of Philips Semiconductors.</li> <li><a href="#">Section 2</a>: modified 'Jedec Std 17' into 'JESD78'</li> <li><a href="#">Section 10</a>: changed propagation delays.</li> </ul>			
74ALVT16823 v.3	19980612	Product specification	-	74ALVT16823 v.2
74ALVT16823 v.2	19980612	Product specification	-	74ALVT16823 v.1
74ALVT16823 v.1	19980303	Product specification	-	-

## 14. Legal information

### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the internet at <https://www.nexperia.com>.

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